

**Search Notes**

Application/Control No.

10/815,162

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

WU, STEPHEN

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	09.08.05	Nh